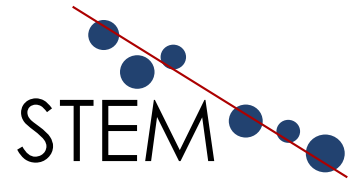

1st Workshop on Statistical Test Methods

29-30 May 2014, Paderborn, Germany
Fringe event to ETS 2014



Call for Papers

In the last years, the introduction of advanced mathematical tools for statistical data processing has opened a number of novel research lines within the field of IC testing. The objective of this workshop is to provide an environment where researchers from academia and industry can discuss their latest findings, approaches, and ongoing work on all aspects of statistical test methods, from purely mathematical advancements to actual production test experiences.

Program will include invited talks, contributed talks and work in progress. Topics of the workshop include but are not limited to:

- Alternate test
- Adaptive test
- Statistical timing models
- Automatic test vector generation
- Statistical fault models
- Statistical test compaction
- Process variation modeling
- Yield modeling
- Aging/reliability modeling

Submissions

Authors are invited to submit an extended summary, between 2 and 6 pages in IEEE conference format. The document shall include sufficient detail about the work to permit a meaningful technical review. All submissions will be peer-reviewed and the accepted summaries will be distributed during the workshop. Submissions can be emailed to stem@imse-cnm.csic.es

Every accepted contribution must have at least one author registered to the workshop. The author is also expected to attend the workshop and present the contribution.

Important dates

Submission deadline: ~~15-03-2014~~ **Extended: 10-04-2014**

Submit to: stem@imse-cnm.csic.es

Notification of acceptance: 15-04-2014

Camera-ready version: 30-04-2014

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